

Search Notes

Application/Control No.

10/619,280

Examiner

Anthony Weier

Applicant(s)/Patent under
Reexamination

RIEKE ET AL.

Art Unit

1794

SEARCHED

| Class | Subclass | Date | Examiner |
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| updated | previous search | 10/29/2007 | AW |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

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